Search Notes			

Application No.		Applicant(s)	
10/017,855		FISHER ET AL.	
Examin r		Art Unit	
Julio J. Maldon	ado	2823	

SEARCHED				
Class	Subclass	Date	Examiner	
430	346 302 313)	ECOC 20/61	84e	
438	671,723371, 719,720	#	Ą	
		,	ļ	
<u> </u>				
			7 10 10 10 10 10 10 10 10 10 10 10 10 10	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		<u> </u>		
	:			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Est (USPAT; USPGPUB);	(3/103/ 3UC)	Sep.	
(lithography a pattering) of (bean & radiation) for (Plood & electron & beam)			
t ((((lithography or pathernia t (been to radiation) of (flood to electron to bean)) t (photoresist)) retching to		Ð	
pulysition)			
	:		
		·	